WHAT IS CLAIMED IS:

1. A socket guider for testing of electronic parts, the socket guider comprising:

a pair of guider bodies provided to support both ends of an electronic part to be inserted into an elongated test slit into which a contact terminal-side portion of the electronic part is inserted; and

a pair of elastic supporters replaceably coupled to the guider bodies, respectively, and configured to maintain a posture of the electronic part by elastically supporting both ends of the electronic part while the contact terminal-side portion is inserted into the test slit or in a state in which the contact terminal-side portion has been inserted into the test slit;

wherein the pair of guider bodies are disposed on both sides of the test slit, respectively, in a direction in which the test slit is elongated; and

wherein the pair of elastic supports are allocated to the pair of guider bodies, respectively, and are detachably installed in the guider bodies, respectively,

wherein:

a guide groove is elongated in each of the guider bodies in a direction, in which the electronic part is moved, in order to guide the electronic part through movement in a process in which the electronic part is inserted into the test slit, and a coupling depression is formed at one point of the guide groove;

each of the elastic supports is a ball plunger provided in a structure in which the ball plunger is inserted into the coupling depressing; and

a ball of the ball plunger presses the electronic part while being elastically supported by a spring.

2. A socket guider for testing of electronic parts, the socket guider comprising:

a pair of guider bodies provided to support both ends of an electronic part to be inserted into an elongated test slit

into which a contact terminal-side portion of the electronic part is inserted; and

a pair of elastic supporters replaceably coupled to the guider bodies, respectively, and configured to maintain a posture of the electronic part by elastically supporting both ends of the electronic part while the contact terminal-side portion is inserted into the test slit or in a state in which the contact terminal-side portion has been inserted into the test slit;

wherein the pair of guider bodies are disposed on both sides of the test slit, respectively, in a direction in which the test slit is elongated; and

wherein the pair of elastic supports are allocated to the pair of guider bodies, respectively, and are detachably installed in the guider bodies, respectively,

wherein each of the elastic supports comprises:

a coupling portion coupled to a corresponding one of the guider bodies;

a guide portion provided with a guide groove elongated in a direction, in which the electronic part is moved, in order to guide the electronic part through movement in a process in which the electronic part is inserted into the test slit; and

at least one elastic portion formed to protrude from the coupling portion toward the guider body so that the coupling portion and the guide portion can be elastically supported on the guider body by means of the elastic portion;

wherein a coupling groove is formed in the guider body to which the coupling portion can be coupled, so that the coupling portion can be coupled to the guider body by being inserted into the coupling groove.

3. The socket guider of claim 2, wherein the coupling portion has a stop protrusion configured to be caught on a back end of the guider body in a process in which the coupling portion is fitted into the coupling groove while moving in a back-front direction.

4. The socket guider of claim 2, wherein the coupling

portion, the guide portion, and the elastic portion are integrated with one another.

5. The socket guider of claim 4, wherein the elastic support is made of a synthetic resin material that can be injection-molded and can also be elastically deformed and restored.

6. The socket guider of claim 2, wherein:

the coupling portion is provided with a fitting depression configured such that the elastic portion is fitted thereinto; and

the elastic portion is coupled to the coupling portion by being fitted into the fitting depression.

7. The socket guider of claim 6, wherein:

the coupling portion and the guide portion are integrated with each other; and

the elastic portion is elastically deformable and restorable, is softer than the coupling portion and the guide portion, and is injection-molded with a synthetic resin material.

8. A socket guider for testing of electronic parts, the socket guider comprising:

a pair of guider bodies provided to support both ends of an electronic part to be inserted into an elongated test slit into which a contact terminal-side portion of the electronic part is inserted;

a pair of elastic supporters replaceably coupled to the guider bodies, respectively, and configured to maintain a posture of the electronic part by elastically supporting both ends of the electronic part while the contact terminal-side portion is inserted into the test slit or in a state in which the contact terminal-side portion has been inserted into the test slit; and

at least one calibration pin coupled to each of the guider bodies to protrude forward, and configured to be mated with a

calibration hole formed in a gripping mechanism to correct a position of the electronic part fed by the gripping mechanism so that the contact terminal-side portion of the electronic part can be precisely inserted into the test slit;

wherein the pair of guider bodies are disposed on both sides of the test slit, respectively, in a direction in which the test slit is elongated; and

wherein the pair of elastic supports are allocated to the pair of guider bodies, respectively, and are detachably installed in the guider bodies, respectively,

wherein the calibration pin is disposed off-centered from an imaginary straight line passing through the test slit in the direction in which the test slit is elongated; and

wherein the calibration hole is disposed off-centered from a plane including one surface of the electronic part gripped by the gripping mechanism.

9. A socket guider for testing of electronic parts, the socket guider comprising:

a pair of guider bodies provided to support both ends of an electronic part to be inserted into an elongated test slit into which a contact terminal-side portion of the electronic part is inserted;

a pair of elastic supporters replaceably coupled to the guider bodies, respectively, and configured to maintain a posture of the electronic part by elastically supporting both ends of the electronic part while the contact terminal-side portion is inserted into the test slit or in a state in which the contact terminal-side portion has been inserted into the test slit; and

first and second calibration pins coupled to each of the guider bodies to protrude forward, and configured to be mated with calibration holes formed in a gripping mechanism to correct a position of the electronic part fed by the gripping mechanism so that the contact terminal-side portion of the electronic part can be precisely inserted into the test slit;

wherein the pair of guider bodies are disposed on both sides of the test slit, respectively, in a direction in which

the test slit is elongated; and

wherein the pair of elastic supports are allocated to the pair of guider bodies, respectively, and are detachably installed in the guider bodies, respectively,

wherein the calibration pins are disposed off-centered from an imaginary straight line passing through the test slit in the direction in which the test slit is elongated, and are spaced apart from each other;

wherein the first calibration pin is used for correcting the position of the electronic part when the electronic part is inserted into the test slit after the electronic part in a laid position has been erected at 90 degrees, and the second calibration pin is used for correcting the position of the electronic part when the electronic part is inserted into the test slit after the electronic part in a laid positon has been erected at -90 degrees; and

wherein the calibration holes are disposed off-centered from a plane including one surface of the electronic part gripped by the gripping mechanism.